



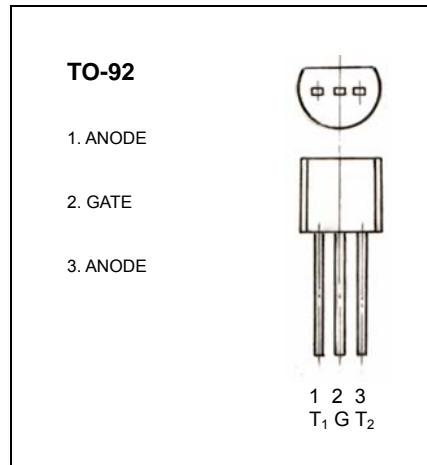
JIANGSU CHANGJIANG ELECTRONICS TECHNOLOGY CO., LTD

## JCST TO-92 Plastic-Encapsulate Transistors

### MAC97A6,A8 TRIAC

#### MAIN FEATURES

Symbol	value	unit
$I_{T(RMS)}$	1	A
$V_{DRM}/V_{RRM}$	MAC97A6	400
	MAC97A8	600
$I_{TSM}$	8	A



#### DESCRIPTION

Logic level sensitive gate triac intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

#### FEATURES

- Blocking voltage to 400 V (MAC97A6)
- RMS on-state current to 0.6 A
- General purpose bidirectional switching

#### APPLICATIONS

- General purpose bidirectional switching
- Phase control applications
- Solid state relays.

#### Limiting values

Symbol	Parameter	Conditions	Value	Unit
$V_{DRM}$	repetitive peak off-state voltage MAC97A6 MAC97A8	$T_j = 25 \text{ to } 125^\circ\text{C}$ $T_j = 25 \text{ to } 125^\circ\text{C}$	400 600	V
$I_{GM}$	gate current(peak value)	$t = 2\mu\text{s} \text{ max}$	1	A
$V_{GM}$	gate voltage(peak value)	$t = 2\mu\text{s} \text{ max}$	5	V
$P_{GM}$	gate power(peak value)	$t = 2\mu\text{s} \text{ max}$	5	W
$T_j$	Junction Temperature	-	-40 to 125	°C
$T_{stg}$	Storage Temperature	-	-40 to 150	°C

## ELECTRICAL CHARACTERISTICS (T<sub>amb</sub>=25°C unless otherwise specified)

Parameter	Symbol	Test conditions	MIN	MAX	UNIT
Rated repetitive peak off-state voltage	V <sub>DRM</sub> , V <sub>RRM</sub>	I <sub>D</sub> =10µA MAC97A6 MAC97A8	400 600		V
Rated repetitive peak off-state current	I <sub>DRM</sub>	V <sub>D</sub> =V <sub>DRM</sub>		10	µA
On-state voltage	V <sub>TM</sub>	I <sub>T</sub> =1A, I <sub>G</sub> =50mA		1.9	V
Gate trigger current	I	I <sub>GT</sub>	T <sub>2</sub> (+), G(+)	V <sub>D</sub> =12V R <sub>L</sub> =100Ω	5 mA
	II		T <sub>2</sub> (+), G(-)		5 mA
	III		T <sub>2</sub> (-), G(-)		5 mA
	IV		T <sub>2</sub> (-), G(+)		- mA
Gate trigger voltage	I	V <sub>GT</sub>	T <sub>2</sub> (+), G(+)	V <sub>D</sub> =12V R <sub>L</sub> =100Ω	1.5 V
	II		T <sub>2</sub> (+), G(-)		1.5 V
	III		T <sub>2</sub> (-), G(-)		1.5 V
	IV		T <sub>2</sub> (-), G(+)		- V
Holding current	I <sub>H</sub>	I <sub>T</sub> =600mA , I <sub>G</sub> =20mA		10	mA

## Typical Characteristics

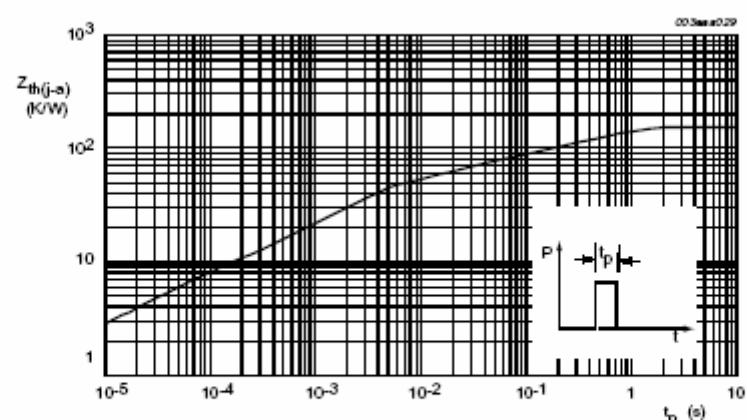
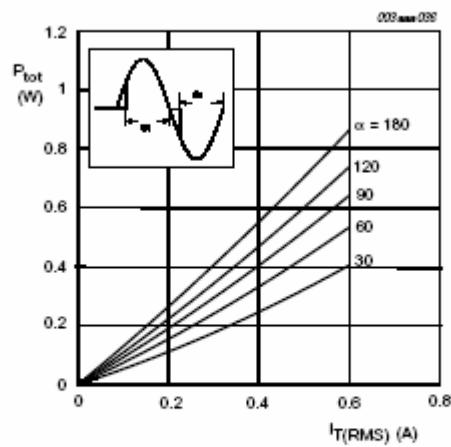
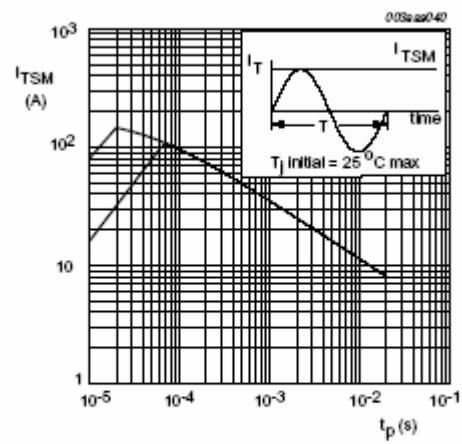


Fig 1. Transient thermal impedance from junction to ambient as a function of pulse duration.



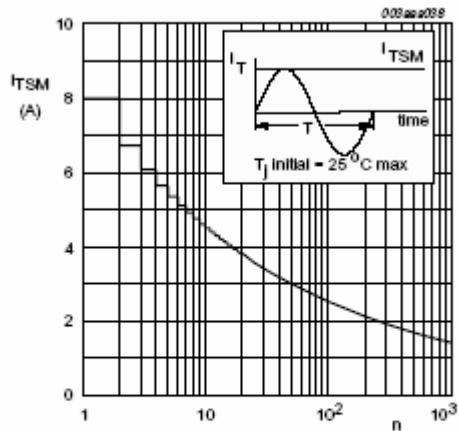
$\alpha$  = conduction angle

**Fig 2. Maximum on-state dissipation as a function of RMS on-state current; typical values.**



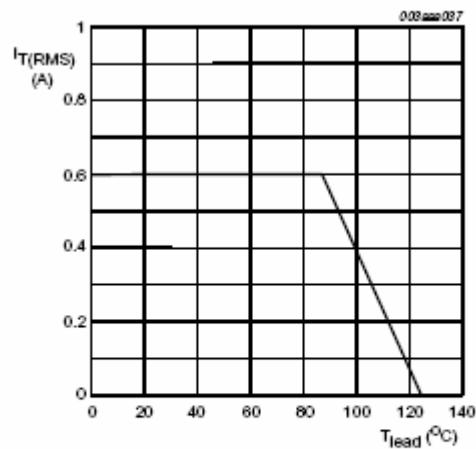
$t_p \leq 20 \text{ ms}$

**Fig 3. Maximum permissible non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; typical values.**

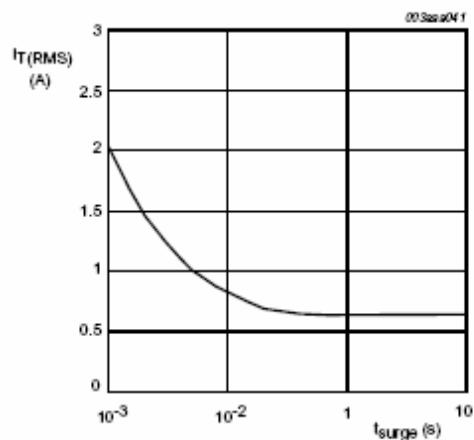


$n$  = number of cycles at  $f = 50 \text{ Hz}$

**Fig 4. Maximum permissible non-repetitive peak on-state current as a function of number of cycles for sinusoidal currents; typical values.**

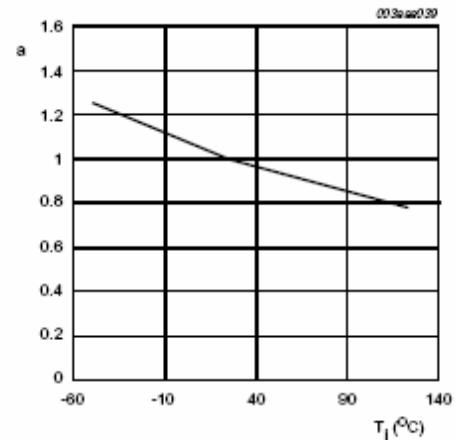


**Fig 5. Maximum permissible RMS current as a function of lead temperature; typical values.**



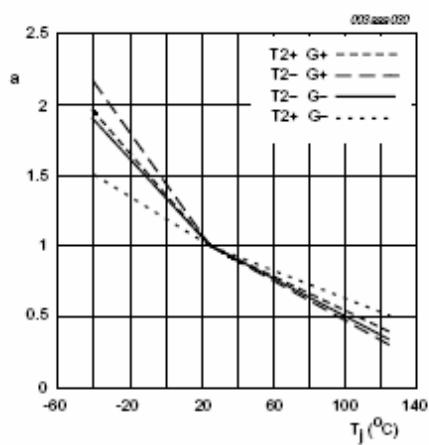
$f = 50 \text{ Hz}; T_{\text{lead}} \leq 50^\circ\text{C}$

**Fig 6. Maximum permissible repetitive RMS on-state current as a function of surge duration for sinusoidal currents; typical values.**



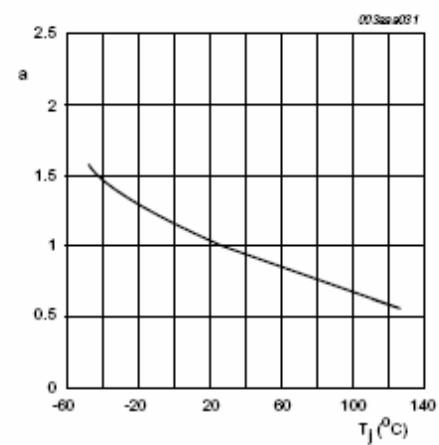
$$a = \frac{V_{GT(T)}}{V_{GT(25^\circ\text{C})}}$$

**Fig 7. Normalized gate trigger voltage as a function of junction temperature; typical values.**



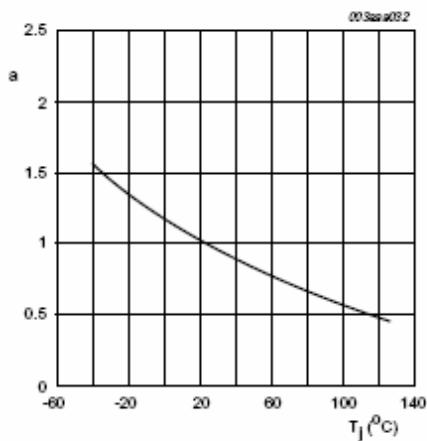
$$a = \frac{I_{GT(T)}}{I_{GT(25^\circ\text{C})}}$$

**Fig 8. Normalized gate trigger current as a function of junction temperature; typical values.**



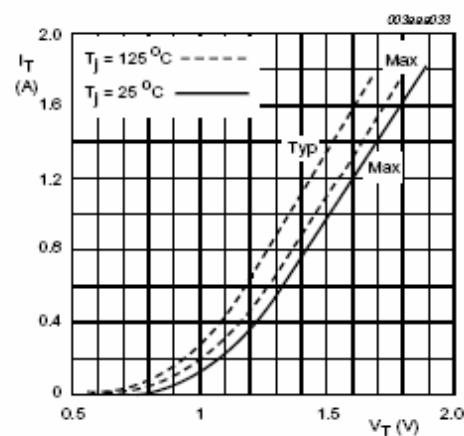
$$a = \frac{I_L(T)}{I_L(25^\circ\text{C})}$$

**Fig 9. Normalized latching current as a function of junction temperature; typical values.**

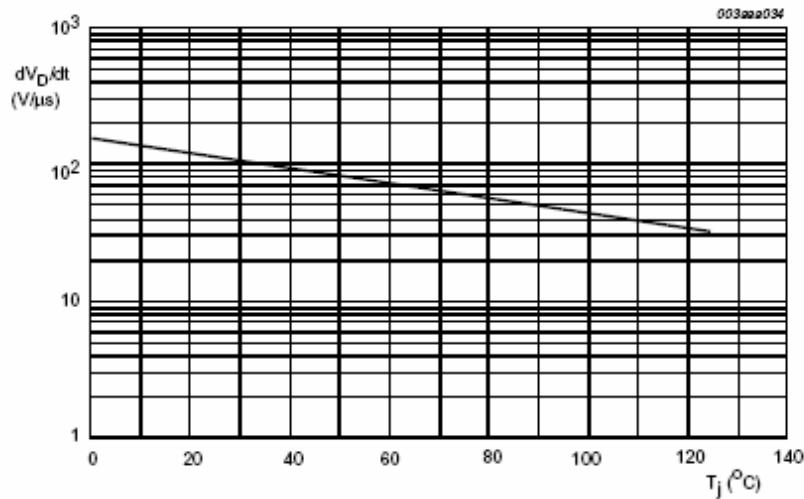


$$a = \frac{I_H(T_j)}{I_H(25^\circ C)}$$

**Fig 10. Normalized holding current as a function of junction temperature; typical values.**



**Fig 11. On-state current as a function of on-state voltage; typical and maximum values.**



**Fig 12. Critical rate of rise of off-state voltage as a function of junction temperature; typical values.**